



Innovation !



CHRocodile IT – Optical Sensor
Contactless measurement of wafers & solar cells



CHRocodile

If time matters...

Sensor Properties

Further Information:
www.CHROcodile.de

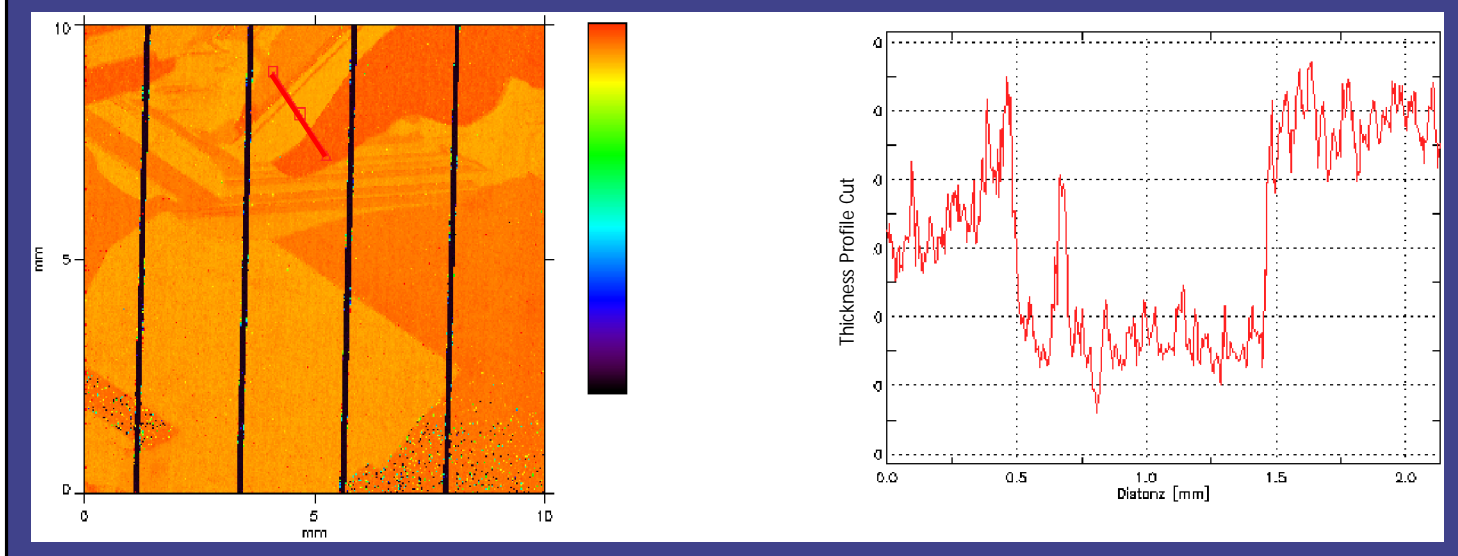
- High accuracy (in Si): down to 70 nm *
- High measuring rate: 4,000 Hz
- Lateral resolution: 6.5 μm
- Si-thickness: 7 μm to 1 mm
- Z-resolution: down to 1 nm *
- Measurement also of GaAs
- Transparent coatings/foils from 17 μm up to 2.3 mm
- Robust measuring head without electronics or light source

*depends on used measuring range

The already well established *CHROcodile IT* sensor performs high-precision, non-contact distance and layer thickness measurements on wafers, solar cells and semiconductors. With a single measuring head, it is capable of measuring up to 1mm thick silicon from one side. Measurements can also be taken on other common infrared transparent materials, such as GaAs. One typical application is the inline thickness measurement of Si-wafers on a conveyor belt.

The basis for this nondestructive measuring method is an interferometric sensor which examines the substrate with infrared light. The *CHROcodile IT* is designed for simple and direct integration into the production process. However, it also serves as an economic and precise measuring tool for laboratory use.

Thickness - scan of a solar cell



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